Acta Crystallographica Section C
Crystal Structure
Communications
ISSN 0108-2701

# (-)-(3S)-4-(2-\{[4,4-Dimethoxy-6-(benzyloxymethyl)perhydropyran-2-yl]methyl\}-1,3-dithian-2-yl)-4-methyl-3-(1,1,2,2-tetramethyl-1-silapropoxy)-pentan-1-ol 

Hiroyuki Hosomi, Shigeru Ohba,* Ken Ohmori, Tetsuo Obitsu, Yasuyuki Ogawa, Yuichi Ishikawa, Shosuke Yamamura and Shigeru Nishiyama

Department of Chemistry, Faculty of Science and Technology, Keio University, Hiyoshi 3-14-1, Kohoku-ku, Yokohama 223-8522, Japan
Correspondence e-mail: ohba@chem.keio.ac.jp
Received 28 February 2000
Accepted 2 March 2000

## Data validation number: IUC0000056

The absolute configuration was determined for the title compound, ( - ) $-\mathrm{C}_{32} \mathrm{H}_{56} \mathrm{O}_{6} \mathrm{~S}_{2} \mathrm{Si}$, (I), which was prepared in a synthetic study on the natural products bryostatins. Two independent molecules show similar conformations, except for the orientation of the methoxy groups.

## Comment

The absolute configuration was determined for the title compound, which was prepared in a synthetic study on the natural products bryostatins. A synthetic study on bryostatin 3 has been reported (Obitsu et al., 1998).

(I)

## Experimental

The optically active title compound was prepared by the authors in a synthetic study on bryostatins (Ohmori et al., 2000). The angle of rotation $[\alpha]_{D}{ }^{22}$ is $-6.24^{\circ}\left(c 1.0, \mathrm{CHCl}_{3}\right)$. Crystals were grown from a hexane/ethyl acetate solution.

## Crystal data

$\mathrm{C}_{32} \mathrm{H}_{56} \mathrm{O}_{6} \mathrm{~S}_{2} \mathrm{Si} \quad D_{x}=1.167 \mathrm{Mg} \mathrm{m}^{-3}$
$M_{r}=629.00$
Monoclinic, $P 2_{1}$
$a=6.878$ (3) $\AA$ 。
$b=19.658$ (3) $\AA$
$c=26.493$ (2) $\AA$
$\beta=91.33$ (2) ${ }^{\circ}$
$V=3581.1$ (17) $\AA^{3}$
$Z=4$

## Data collection

Rigaku AFC-5 diffractometer
$\omega$ scans
Absorption correction: by integra-
tion (Coppens et al., 1965)
$T_{\text {min }}=0.881, T_{\text {max }}=0.977$
7078 measured reflections
6497 independent reflections
4622 reflections with $I>2 \sigma(I)$

## Refinement

Refinement on $F^{2}$
$R(F)=0.051$
$w R\left(F^{2}\right)=0.130$
$S=1.02$
6497 reflections
745 parameters
H atoms treated by a mixture of independent and constrained refinement
$R_{\text {int }}=0.030$
$\theta_{\text {max }}=25^{\circ}$
$h=0 \rightarrow 8$
$k=0 \rightarrow 23$
$l=-31 \rightarrow 31$
3 standard reflections every 100 reflections intensity decay: $1.0 \%$
$w=1 /\left[\sigma^{2}\left(F_{o}{ }^{2}\right)+(0.0591 P)^{2}\right.$
$+1.2827 P]$
where $P=\left(F_{o}{ }^{2}+2 F_{c}{ }^{2}\right) / 3$
Mo $K \alpha$ radiation
Cell parameters from 25 reflections
$\theta=14.3-15.0^{\circ}$
$\mu=0.220 \mathrm{~mm}^{-1}$
$T=298$ (1) K
Plate-like, colourless
$0.7 \times 0.6 \times 0.1 \mathrm{~mm}$
$(\Delta / \sigma)_{\text {max }}=0.017$
$\Delta \rho_{\max }=1.00 \mathrm{e} \AA^{-3}$
$\Delta \rho_{\min }=-0.29 \mathrm{e}^{\AA^{-3}}$
Absolute structure: Flack (1983), no Friedel pairs
Flack parameter $=0.0(1)$

Table 1
Selected geometric parameters $\left({ }^{\circ},{ }^{\circ}\right)$.

| S1-C10 | 1.805 (7) | Si3-O8 | 1.648 (4) |
| :---: | :---: | :---: | :---: |
| S1-C13 | 1.859 (5) | Si3-C36 | 1.856 (8) |
| S2-C12 | 1.807 (7) | Si3-C37 | 1.864 (10) |
| S2-C13 | 1.843 (6) | Si3-C38 | 1.878 (8) |
| S51-C60 | 1.807 (7) | Si53-O58 | 1.663 (5) |
| S51-C63 | 1.861 (5) | Si53-C86 | 1.845 (8) |
| S52-C62 | 1.829 (7) | Si53-C87 | 1.853 (9) |
| S52-C63 | 1.836 (5) | Si53-C88 | 1.876 (8) |
| Si3-O8-C33 | 128.8 (4) | Si53-O58-C83 | 128.8 (4) |

Table 2
Hydrogen-bonding geometry $\left(\AA,{ }^{\circ}\right)$.

| $D-\mathrm{H} \cdots A$ | $D-\mathrm{H}$ | $\mathrm{H} \cdots A$ | $D \cdots A$ | $D-\mathrm{H} \cdots A$ |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{O} 9-\mathrm{H} 9 \ldots \mathrm{O} 4^{\text {i }}$ | 0.97 (5) | 2.17 (6) | 3.035 (6) | 147 (5) |
| O9-H9 . . $\mathrm{O}^{\text { }}{ }^{\text {i }}$ | 0.97 (5) | 2.41 (4) | 3.188 (7) | 136 (5) |
| O59-H59 . . $\mathrm{O}^{\text {5 }}{ }^{\text {ii }}$ | 0.98 (5) | 2.30 (6) | 3.096 (6) | 138 (5) |
| O59-H59 . ${ }^{\text {O } 57}{ }^{\text {ii }}$ | 0.98 (5) | 2.28 (5) | 3.082 (7) | 139 (5) |

Symmetry codes: (i) $-x, \frac{1}{2}+y, 2-z$; (ii) $-1-x, \frac{1}{2}+y, 1-z$.
Hydroxyl H atoms were located from a difference synthesis and their positional parameters were refined with a restraint of $\mathrm{O}-\mathrm{H}=$ $0.98 \AA$ (s.u. $0.01 \AA$ ) and with $U_{\text {iso }}(\mathrm{H})=1.2 U_{\text {eq }}$ (parent atom). The other H -atom positional parameters were calculated geometrically and fixed with $U_{\text {iso }}(\mathrm{H})=1.2 U_{\text {eq }}$ (parent atom). A maximum residual density of $1.00 \mathrm{e}^{-3}$ was located $1.11 \AA$ from the C88 atom, suggesting an orientational disorder of the tetramethylsilapropoxy
group. The absolute structure was determined based on a Flack parameter value of $0.0(1)$, which is consistent with the expected absolute configuration of $3 S$ produced by Sharpless asymmetric epoxidation protcol. The two independent molecules are related approximately by a translation of $(0.47,-0.05,0.50)$, except for the methoxy O atoms.

Data collection: MSC/AFC Diffractometer Control Software (Molecular Structure Corporation, 1993); cell refinement: MSC/AFC Diffractometer Control Software; data reduction: TEXSAN (Molecular Structure Corporation, 1999); program(s) used to solve structure: SiR92 (Altomare et al., 1994); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); software used to prepare material for publication: TEXSAN.

## References

Altomare, A., Cascarano, G., Giacovazzo, C., Guagliardi, A., Burla, M. C., Polidori, G. \& Camalli, M. (1994). J. Appl. Cryst. 27, 435.
Coppens, P., Leiserowitz, L. \& Rabinovich, D. (1965). Acta Cryst. 18, 10351038.

Flack, H. D. (1983). Acta Cryst. A39, 876-881.
Molecular Structure Corporation (1993). MSC/AFC Diffractometer Control Software. MSC, 3200 Research Forest Drive, The Woodlands, TX 77381, USA.
Molecular Structure Corporation (1999). TEXSAN. Version 1.10. MSC, 3200 Research Forest Drive, The Woodlands, TX 77381, USA.
Obitsu, T., Ohmori, K., Ogawa, Y., Hosomi, H., Ohba, S., Nishiyama, S. \& Ymamura, S. (1998). Tetrahedron Lett. 39, 7349-7352.
Ohmori, K., Obitsu, T., Ogawa, Y., Ishikawa, Y., Yamamura, S. \& Nishiyama, S. (2000). In preparation.

Sheldrick, G. M. (1997). SHELXL97. University of Göttingen, Germany.

